



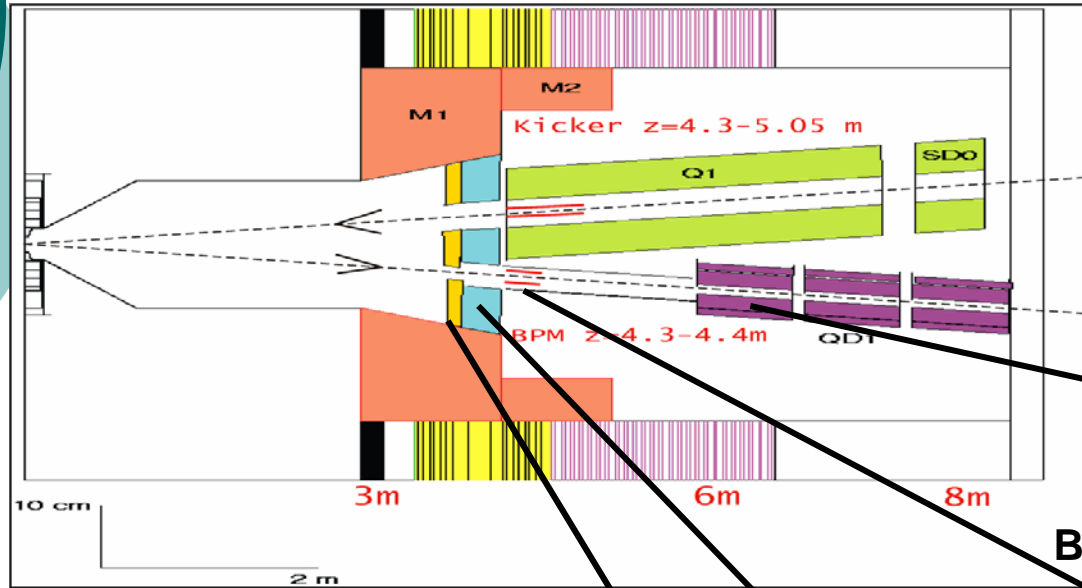
# Font@ESA (T-488)

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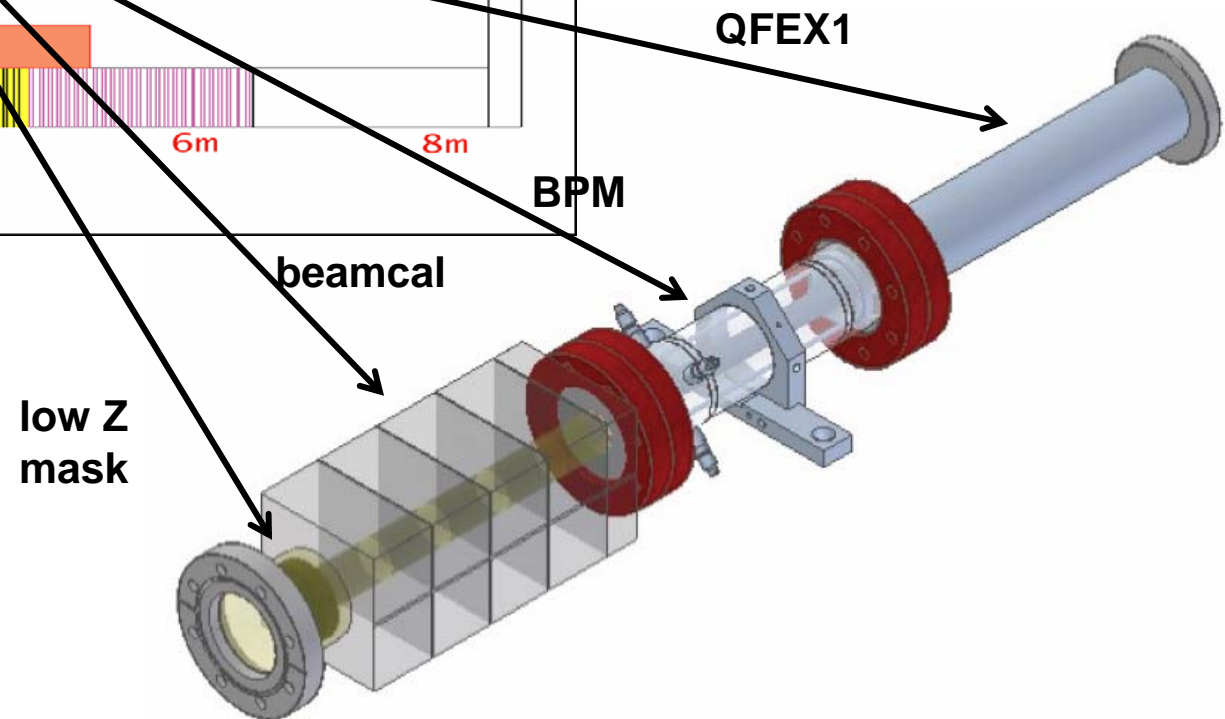
FONT: C Clarke, C Swinson, P Burrows, T Hartin, G Christian, H Dabiri-Khah

SLAC: Mike Woods, Ray Arnold, Steve Smith et al

# FONT ESA Test Module -design

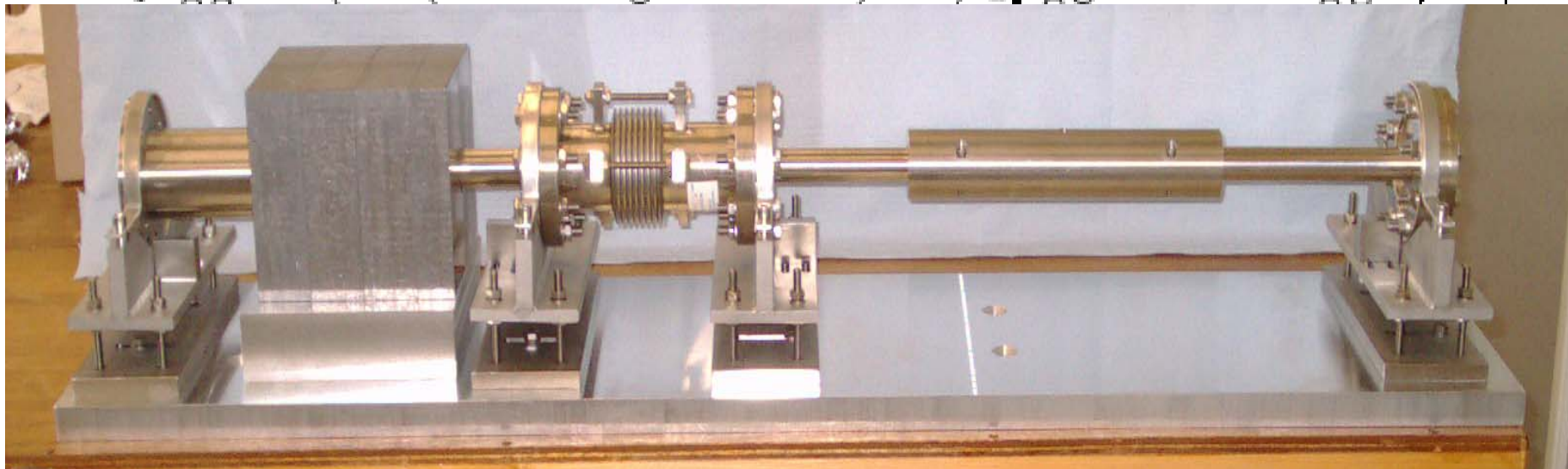
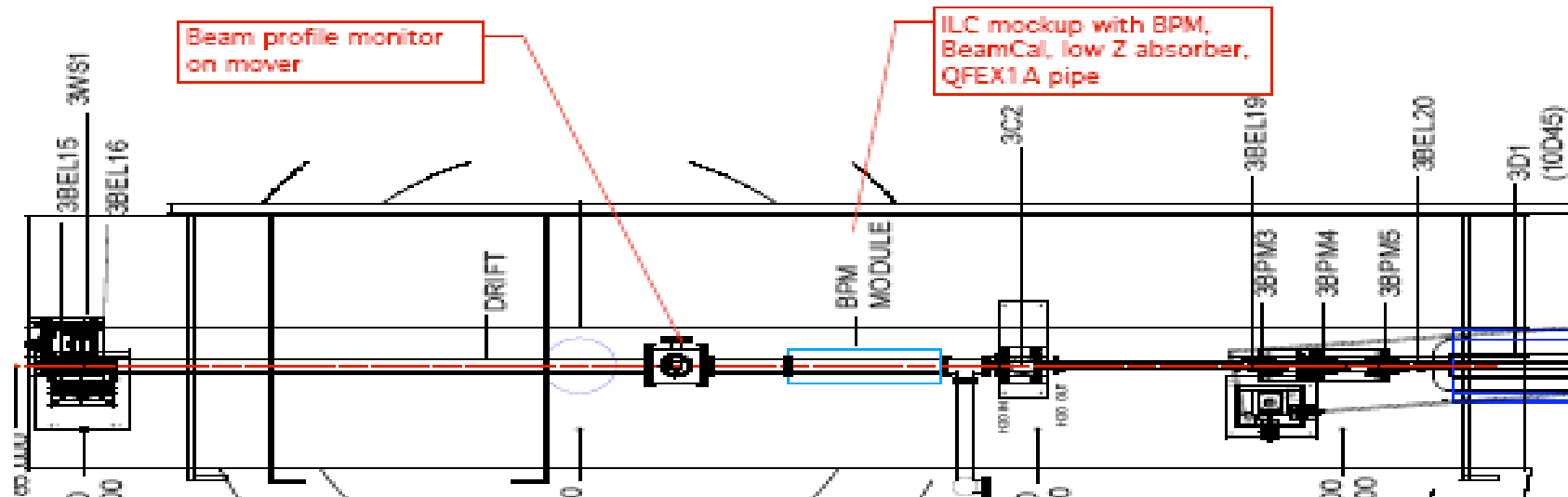


**Material model  
of ILC outgoing  
beamline**



# FONT ESA Test Module –in situ

FONT Spray Beam Test Layout in SLAC ESA



# Beam test outline

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## AIM: Recreate ILC-like background hits on BPM

- Pass 30 GeV main beam through Be radiator, select momentum bites and transport to A-line
- bunch charge  $10^6 \rightarrow 10^{10}$  obtained by varying transmission at slits
- x,y shift beam to impinge on lowZ mask and produce spray

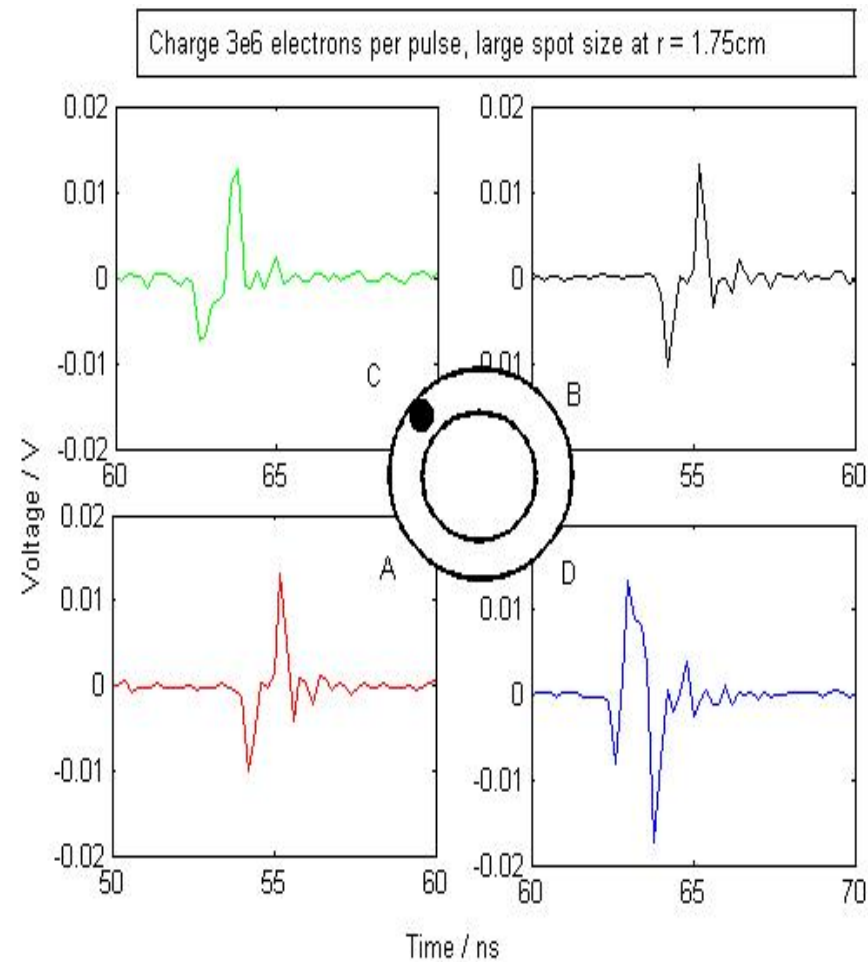
### ILC/ESA Comparison

**ESA:** initial  $10^6$  charge bunch produces  $\sim 2 \times 10^6$   $e^+e^-$  per strip

**ILC:** scheme 14,  $\sim 2 \times 10^4$   $e^+e^-$  per strip

# Raw voltage from BPM pickoffs

- main component is the usual bipolar doublet – 1 ns between peaks reflects the 30cm round trip up and down the strip
- secondary “noise” feature apparent in BPM D – “noise” to “signal” ratio should be the greatest here for this configuration

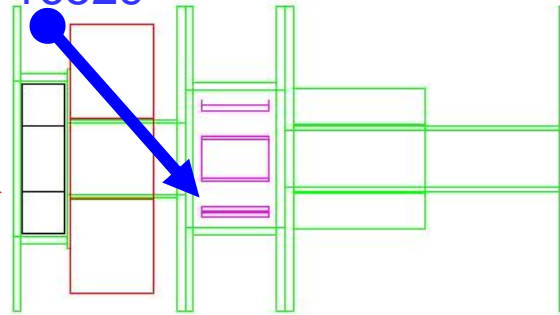




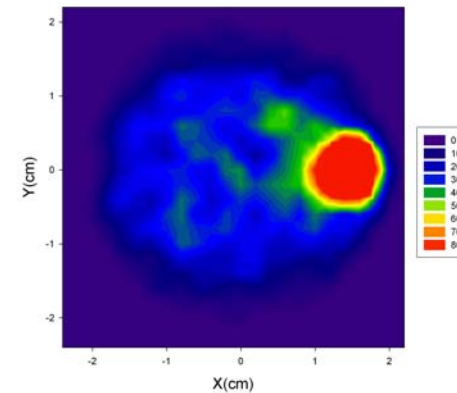
# Geant Data

Net Q at upstream end of  
BPM strips  $Q = -16529$

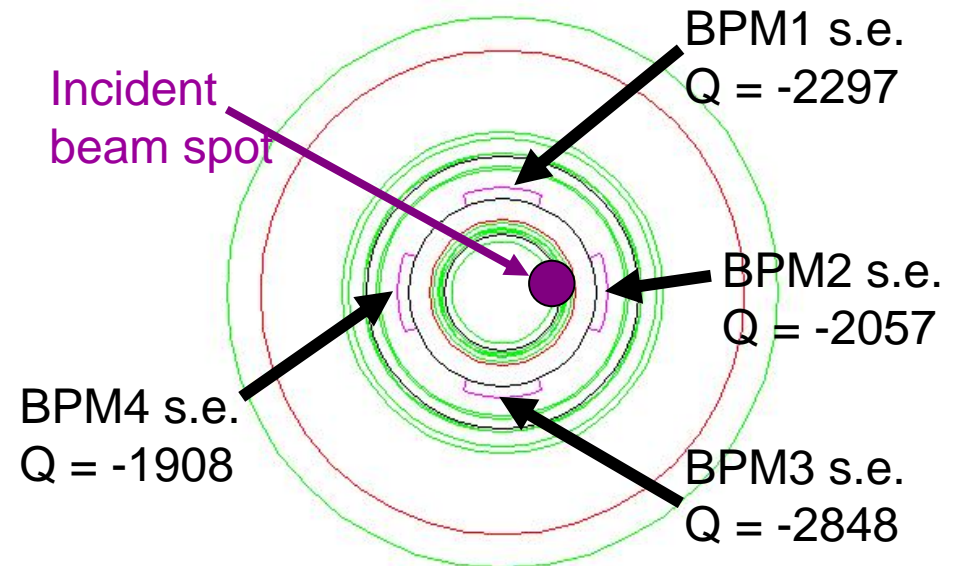
Incident  
 $Q = -10000$



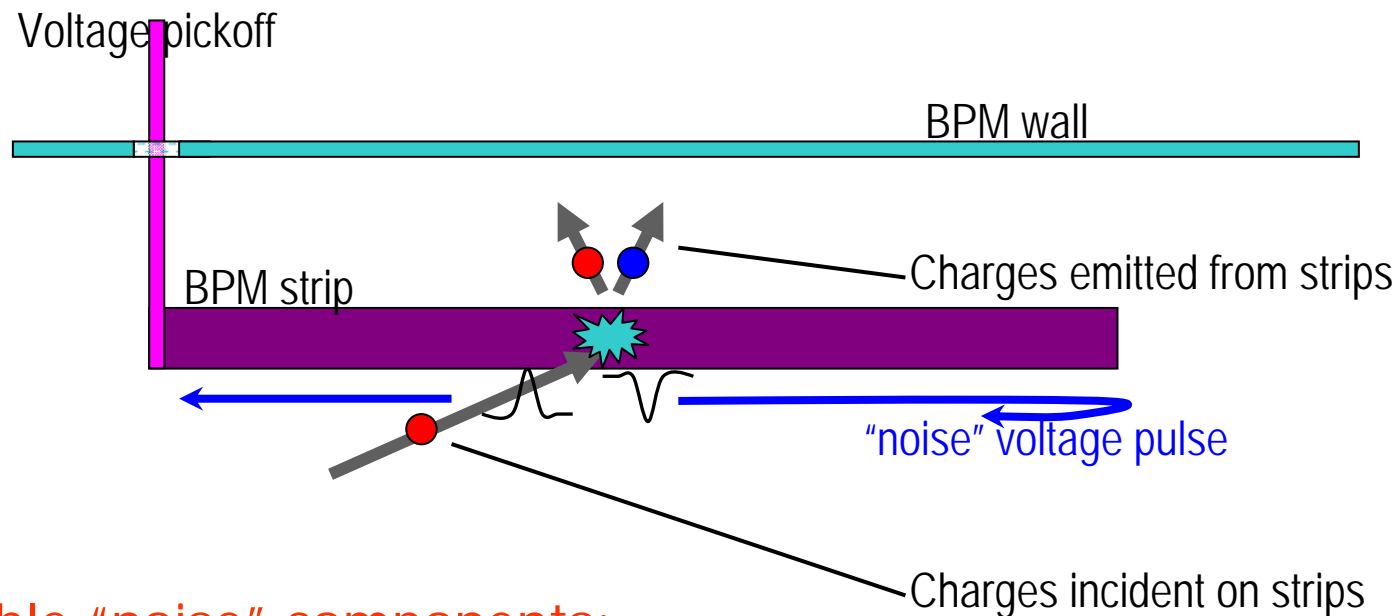
XY contour plot for charges at upstream end  
of the BPM strips



- 1mm spot size incident on low Z at  $(x,y)=(1.4,0)$
- “Signal” obtained by counting net charge passing by strips
- “Noise” obtained by counting net charge in the secondary emission from the striplines
- Time response obtained from GEANT T.O.F. parameter



# How to model the noise?



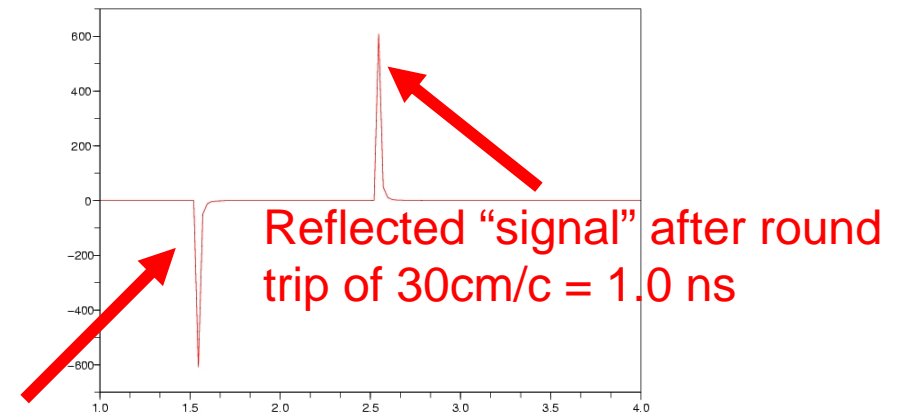
## Possible "noise" components:

- Incident hits – partly make up the "signal" as main charge bunch passes voltage pickoff – these are generally tangential – must take into account the change in image charge. Charges moving toward a strip roughly balanced by those moving away from it, so no net effect from incident hits
- Emitted hits – electrons yield positive (+ reflected negative) voltage pulse, positrons the opposite. Reflected voltage pulse "piles up"

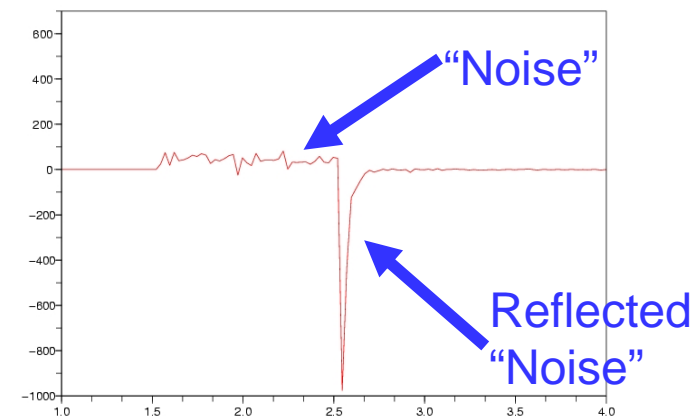
# TOF histogram “raw” charges

This is “raw” because...

- we have to balance signal against noise by taking into account the fraction of the image charge on each strip
- we want to compare with real voltage measurements, take into account residual impedance and capacitance in the measuring circuit

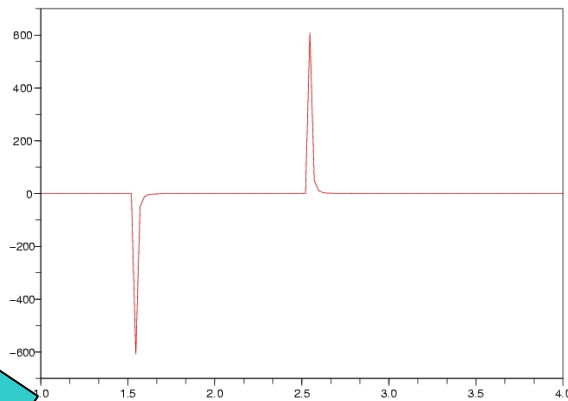


“signal” is almost a delta function at upstream end of BPM strips

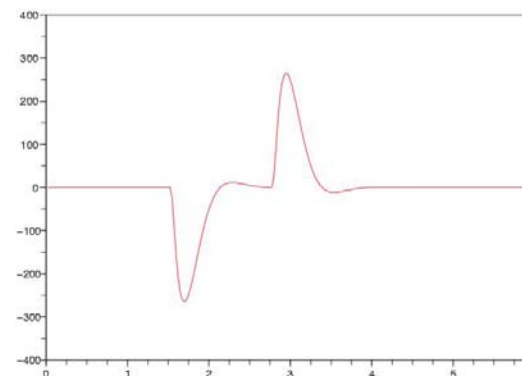
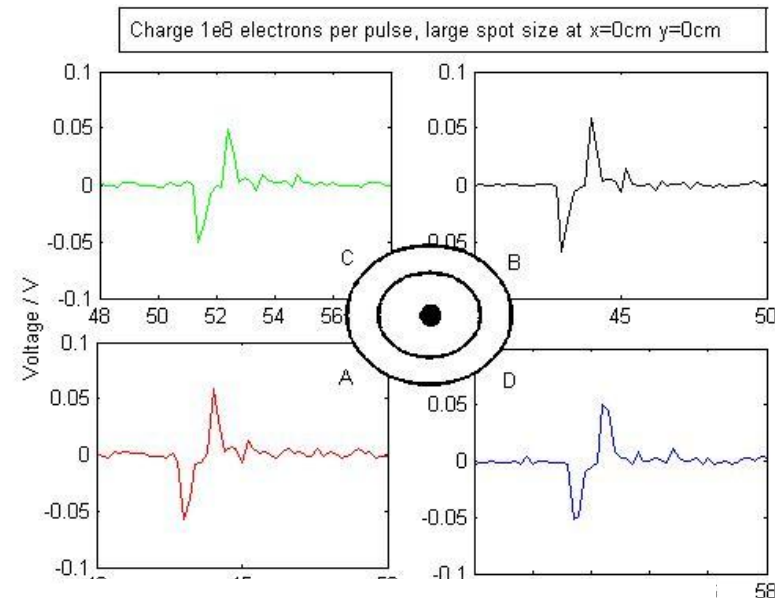




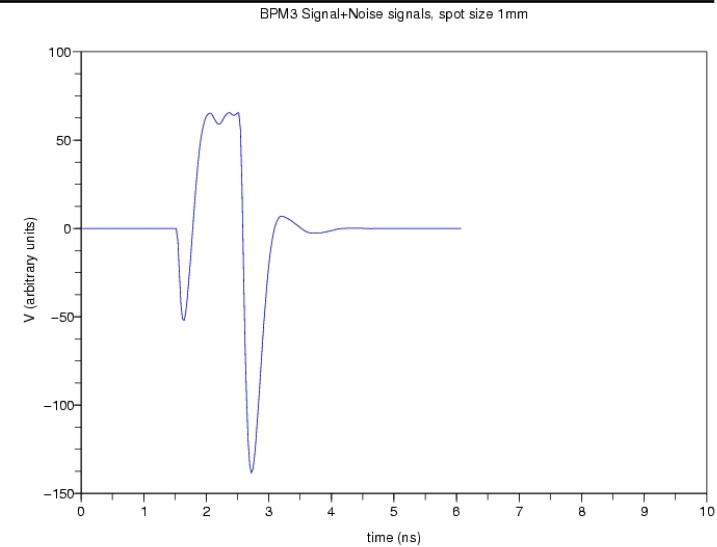
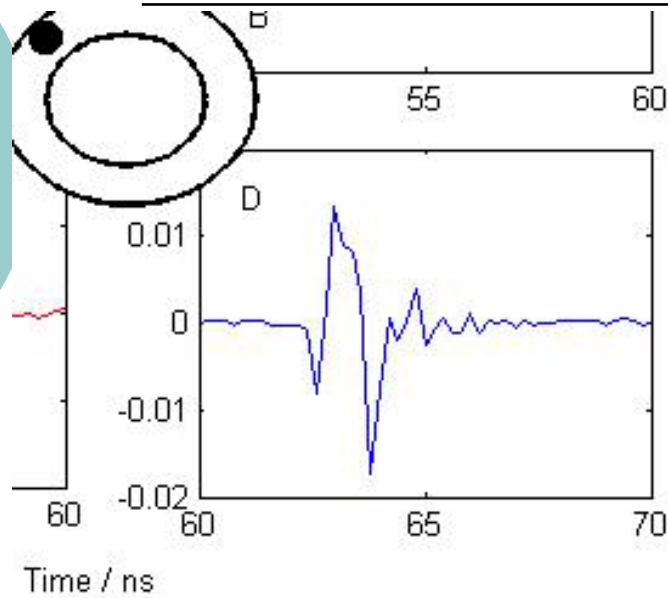
# Simulate measured voltages



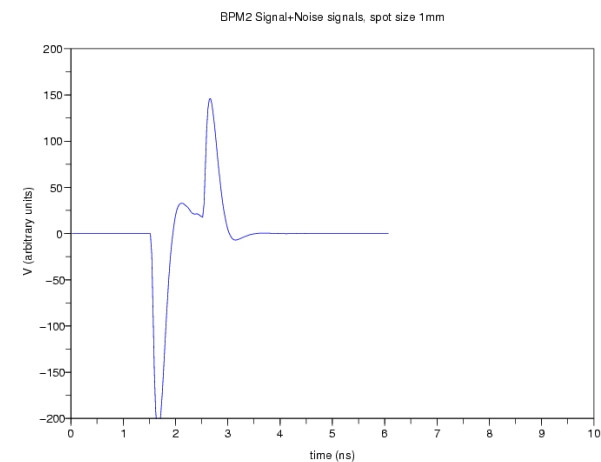
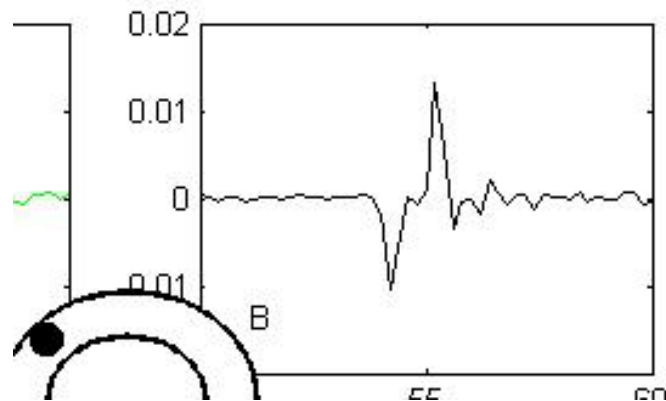
Broaden analytic  
signal pulse by  
passing through a  
2<sup>nd</sup> order 1.2 GHz  
Butterworth Low  
pass filter



# Simulated Signal+Noise results

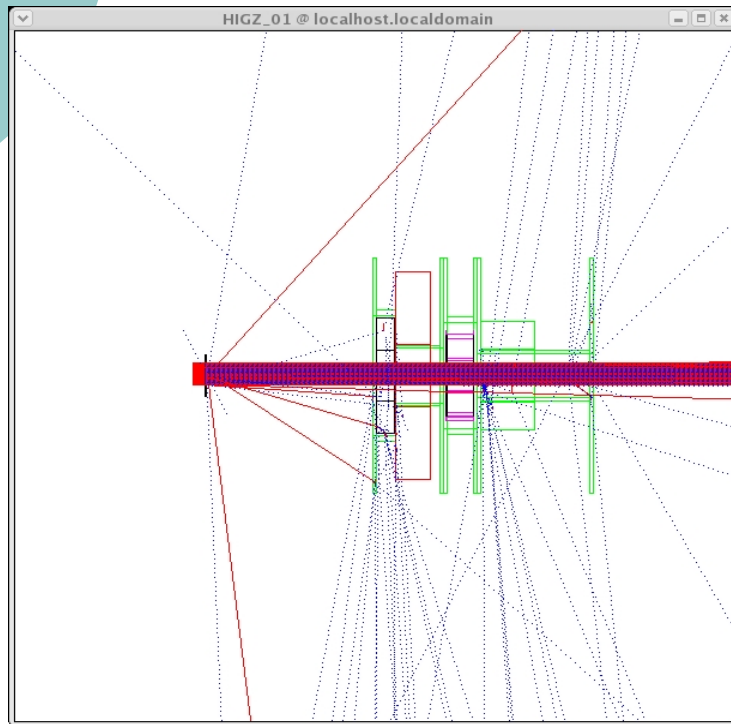


pulse, large spot size at  $r = 1.75\text{cm}$



# New ESA run 2007

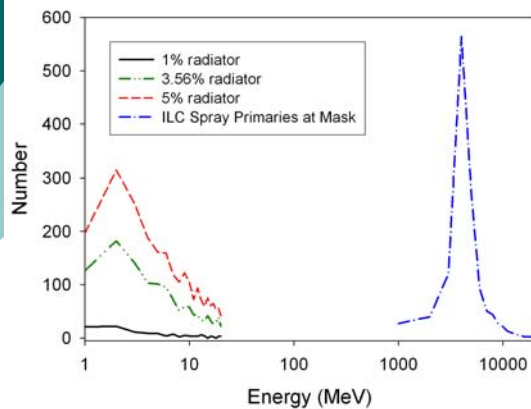
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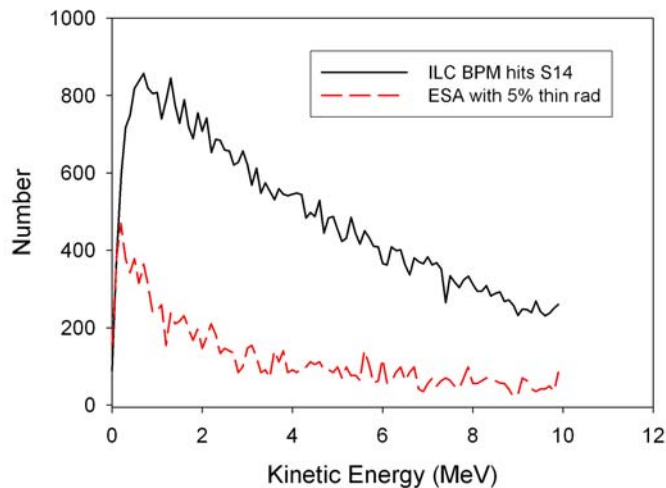
- 2006 run aimed the primary beam at LowZ mask directly – noise to signal higher than we can expect at ILC
- Modify the module to include thin radiator
- Match spray to expected ILC spray

# Geant studies to compare ILC and ESA

Energy spectrum of emitted electrons from an Aluminium thin radiator - Comparison with ILC Spray Primaries at z=3.12m



Energy spectrum of BPM hits



- Energy spectra at LowZ mask different between ILC/ESA, but...
- At BPM strips the spectra is similar
- 5% Al radiator ~ 1m upstream of lowZ mask delivers noise:signal ratio twice that of ILC-can adjust down



## Further work

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- Further data run at ESA in 2007
  - Insert thin radiator upstream of LowZ mask
  - Attach FONT processor to gauge effect of noise on processed signal
- Firm up simulations by
  - Theoretical considerations of noise
  - Full electromagnetic simulation